

**Search Notes**

Application/Control No.

10/564,086

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under  
Reexamination

BIAIS, FRANCOIS

Art Unit

2834

**SEARCHED**

Class	Subclass	Date	Examiner
310	214	2/15/2006	HN
310	215	2/15/2006	HN
310	216	2/15/2006	HN
310	52	2/15/2006	HN
310	54	2/15/2006	HN
310	58	2/15/2006	HN
310	64	2/15/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR